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## **Supplementary Information**

# Ultrathin MoS<sub>2</sub> Flakes Embedded in Nanoporous Graphene Films for a Multi-

## **Functional Electrode**

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### Calculation of capacitance of supercapacitors

The volumetric specific capacitance ( $C_a$ , F cm<sup>-3</sup>) was determined based on the GDC curves using the following equation:

$$C_{cell} = I/(\Delta V/\Delta t)$$
<sup>(1)</sup>

Where  $\Delta V$ , *I*, and  $\Delta t$  correspond to the potential window (excluding IR drop), discharge time and discharge current, respectively. The volumetric capacitance (C<sub>v</sub>) of the mSC was calculated according to the equation, C<sub>v</sub> = C<sub>cell</sub>/V<sub>cell</sub>, where V<sub>cell</sub> is the total effective volume of the mSC is determined by the active volume of micro-supercapacitor (0.0001071 cm<sup>3</sup>, see Figure S10), the summation of both positive and negative electrode area. (The areal capacitance of MoS2/NGF is 9.9 mF cm<sup>-2</sup>)

The energy density (E) and power density (P) of the device were calculated based on the following equations:

$$E = 1/2C_{\rm v}\Delta V^2 \tag{2}$$

$$P = E/\Delta t \tag{3}$$

$$E = \frac{1}{2 \times 3600} \times 55F/cm^3 \times 1^2 = 0.00763 Wh/cm^3$$
$$P = \frac{0.00763 Wh/cm^3}{28s} \times 3600 = 1 Wh/cm^3$$



Figure S1. Raman spectra of 2H-MoS<sub>2</sub> with different concentration of ATTM.

The optimized content of ammonium tetrathiomolybdate (ATTM, 40 mg) to create few-layer  $MoS_2$  sheets was determined by the Raman spectra. A 20 mg sample was discarded due to low yield.



Figure S2. Contact angle of NGF and MoS<sub>2</sub>/NGF.



**Figure S3.** Low-magnification TEM images of MoS<sub>2</sub>/NGF.



Figure S4. EDAX mapping of the elements present in  $MoS_2/NGF$ .



Figure S5. Normalized sheet resistance of NGF, MoS<sub>2</sub>/NGF and MoS<sub>2</sub>.



Figure S6. Raman spectra of NGF and MoS<sub>2</sub>/NGF.

NGF displayed a D peak at around 1347 cm<sup>-1</sup>, a sharp G peak at 1588 cm<sup>-1</sup>, and a 2D peak at 2697 cm<sup>-1</sup>. Compared to pristine NGF,  $MoS_2/NGF$  exhibited a much higher intensity in the D peak, suggesting that the ultrathin  $MoS_2$  promotes the formation of defect sites for hydrogen-sulfide binding.



Figure S7. X-ray photo-electron spectroscopy (XPS) of the MoS<sub>2</sub>/NGF: c) C1s, d) O1s

Figure S7 shows the XPS C 1s spectrum of MoS<sub>2</sub>/NGF. C 1s peaks of the as-prepared MoS<sub>2</sub>/NGF were deconvoluted into four peaks at binding energies of 284.0 (sp<sup>2</sup> carbon peak), 284.8 (sp<sup>3</sup>), 285.3 (covalent C-S), 286.1 (C-O) eV, which suggested the presence of functional groups at edge sites and defects in the inner pores. The result of O 1s spectra indicated the presence of different oxygen functional groups, such as C-O, C=O and Ni-O at binding energies of 532.0 eV, 529.2 eV and 532.8 eV, respectively.



Figure S8. Atomic force microscopy image of MoS<sub>2</sub>/NGF film.



Figure S9. Cyclic voltammogram profiles of MoS<sub>2</sub>/NGF in the three-electrode system.



Figure S10. Capacitance retention of MoS<sub>2</sub>/NGF in the three-electrode system.

We achieved almost 100 % of capacitance retention after 20,000 cycles in 1M sulfuric acid electrolyte in the three-electrode system.



**Figure S11.** Cyclic voltammogram profiles of the NGF and  $MoS_2/NGF$  mSC (scan rate = 1 to 100 mV s<sup>-1</sup>) and galvanostatic charge/discharge curves of the NGF and  $MoS_2/NGF$  mSC.



**Figure S12.** (a) Cyclic voltammogram profiles of the  $MoS_2$  on NGF (simple deposition) and  $MoS_2/NGF$  (direct growth) mSC (scan rate = 20 mV s<sup>-1</sup>). b) Galvanostatic charge/discharge curves of the  $MoS_2$  on NGF and  $MoS_2/NGF$  mSC (current density = 1 A cm<sup>-3</sup>). c) Nyquist plot of the  $MoS_2$  on NGF and  $MoS_2/NGF$  mSC. The inset is a close-up image at the high frequency region. d) Bode plot of the  $MoS_2$  on NGF and  $MoS_2/NGF$  mSC.

Figure **S12a** shows the CV curves of a single unit mSC in the potential window of 0-1.0V.  $MoS_2/NGF$  showed a rectangular shape than simple  $MoS_2$  loading on NGF, indicating the improved capacitive performances originated from the interconnected structure of  $MoS_2/NGF$ . Figure **S12b** shows the galvanostatic charge/discharge curves (GCD) at a current density of 0.5 A cm<sup>-3</sup>.  $MoS_2/NGF$  and  $MoS_2$  on NGF retained a quasi-triangular shape, but  $MoS_2$  on NGF shows much higher IR drop during discharge process. Figure **S12c**, The  $MoS_2/NGF$  mSC exhibited a smaller equivalent circuit resistance (215  $\Omega$ ) compared to  $MoS_2$  on NGF (1,500  $\Omega$ ). The phase angle of the mSC was almost same for the  $MoS_2/NGF$  and  $MoS_2$  on NGF.

Contact pad	Series	Parallel	
	Total electrode area  = 1.785 cm <sup>2</sup> Total electrode volume = 0.0003213 cm <sup>3</sup>		
Interspace (/ ) 500 μm			
	Material	Thickness	
Width ( <i>W</i> ) 500 μm	PET layer	20 µm	
Total electrode area = 0.595 cm <sup>2</sup>	MoS <sub>2</sub> /NFG layer	1.8 µm	
Total electrode volume = 0.0001071 cm <sup>3</sup>			
(including interspace)			

Figure S13. Dimensional information of single, series and parallel integrated  $MoS_2/NGF$  micro-supercapacitor and cross-sectional schematic image of micro-supercapacitor



Figure S14. Cross-sectional SEM images of MoS<sub>2</sub>/NGF film.

The thicknesses of  $MoS_2/NGF$ , controlled by adjusting the spin-coating rate, were 800 nm and 1.8  $\mu$ m for 3,000 rpm and 2,000 rpm, respectively.

Active Material	Method	Current Collector	Potential Window	Electrolyte	Specific Capacitance	Ref. No.
Co <sub>3</sub> O <sub>4</sub>	Lithography /Sputtering deposition	Cr	2V	LiPON	14 F/cm <sup>3</sup> @ RT 37 F/cm <sup>3</sup> @ 90 C <sup>o</sup>	8
MoS <sub>2</sub> -LIG	CO <sub>2</sub> Laser beam	MoS <sub>2</sub> -LIG	1V	PVP/NaCl	16mF/cm <sup>2</sup>	9
MnO <sub>x</sub>	Electron beam evaporation	Au/Cr	0.8 V	PVA/H <sub>2</sub> SO <sub>4</sub>	32.8 F/cm <sup>3</sup>	10
MWCNT	Plasma jet etching	MWCNT	0.8 V	PVA/H <sub>3</sub> PO <sub>4</sub>	2.02 F/cm <sup>3</sup>	15
rGO	Pulsed UV laser	rGO	1.2 V	0.1M Na <sub>2</sub> SO <sub>4</sub>	288.7 mF/cm <sup>3</sup>	11
GO ink	3D Printing	Au	1V	PVA/H <sub>2</sub> SO <sub>4</sub>	828.06 mF/cm <sup>3</sup>	12
Cu(OH) <sub>2</sub> @ FeOOH nanotube	Screen printing	Cu	1.5 V	Fumed silica [EMIM][BF4] ionogel	32.2 F/cm <sup>3</sup>	32
MWCNT /Mn <sub>3</sub> O <sub>4</sub>	Photolithography LBL assembly	E-beam Ti/Au	1.2 V	PMMA-PC- LiClO <sub>4</sub>	8.9 F/cm <sup>3</sup>	S8
Photoresist derived porous carbon	Photolithography	Cu/Ni tape	0.8 V	0.5 M H <sub>2</sub> SO <sub>4</sub>	11 F/cm <sup>3</sup>	24
MoS <sub>2</sub> /NGF	Film transfer	NGF	1 V	PVA/H <sub>3</sub> PO <sub>4</sub>	55 F/cm <sup>3</sup>	This work

 Table S1. Comparison of micro-supercapacitors.

Active Material	Max energy density	Max power density	Ref. No.
Carbon	0.18 mWh cm <sup>-3</sup>	0.4 W cm <sup>-3</sup>	15
LbL-MWNT/Mn <sub>3</sub> O <sub>4</sub>	1.8 mWh cm <sup>-3</sup>	4.4 W cm <sup>-3</sup>	S8
PEDOT	$2.98 \text{ mWh cm}^{-3}$	$0.42 \text{ W cm}^{-3}$	25
C/CHIT-CNT	4.5 mWh cm <sup>-3</sup>	0.20 W cm <sup>-3</sup>	26
MWNT/Mn <sub>3</sub> O <sub>4</sub>	2.4 mWh cm <sup>-3</sup>	8 W cm <sup>-3</sup>	S12
LSG/ZnO	1.2 mWh cm <sup>-3</sup>	0.07 W cm <sup>-3</sup>	27
GO	0.43 mWh cm <sup>-3</sup>	9.4 W cm <sup>-3</sup>	28
Bi <sub>6</sub> O <sub>6</sub> (OH) <sub>3</sub> ](NO <sub>3</sub> ) <sub>3</sub> • 1.5H <sub>2</sub> O Bi <sub>2</sub> O(OH) <sub>2</sub> SO <sub>4</sub>	0.125 mWh cm <sup>-3</sup>	0.053 W cm <sup>-3</sup>	33
3D printing CNT	$0.12 \text{ mWh cm}^{-3}$	3.72 W cm <sup>-3.</sup>	19
MoS <sub>2</sub> /NGF	7.64 mWh cm <sup>-3</sup>	9.96 W cm <sup>-3</sup>	This work

 Table S2. Comparison of energy/power densities of micro-supercapacitors.

Thickness by rpm	Capacitance
2.5 μm 1,000 rpm	80 F/cm <sup>3</sup> (Brittle)
1.8 μm 2,000 rpm	55 F/cm <sup>3</sup> (Flexible)
800 nm 3,000 rpm	13 F/cm <sup>3</sup> (Flexible)

Table S3. Specific capacitance changes according to the electrode thickness of  $MoS_2/NGF$ .

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